

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination WAUGH ET AL.	
		Examiner Richard Schnizer, Ph. D.	Art Unit 1635	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B US-5,989,545	11-1999	Foster et al.	424/183.1
C	US-			
D	US-			
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J	US-			
K	US-			
L	US-			
M	US-			

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**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
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